Capital Products & Review

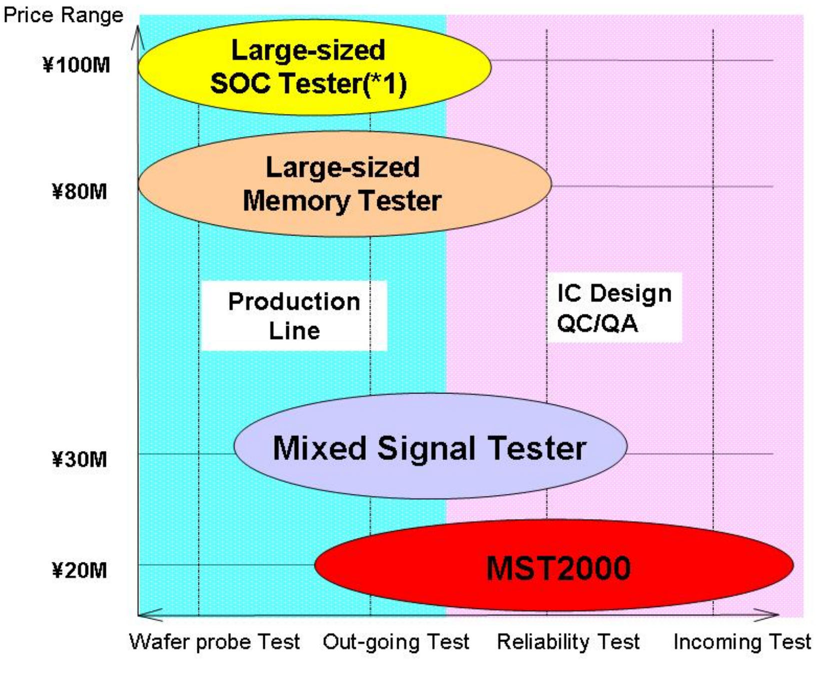
Low cost, High performance/Bench-top LSI tester 『MST2000』

Jepico Corp. Kunitachi R&DCenter
http://www.jepico.co.jp

This tester is most suitable for various purposed such as the evaluation of IC designs, production lines, and incoming tests.

■ LSI tester and MST2000

MST2000 is the bench-top LSI tester for linear LSI, digital LSI, mixed-signal LSI and any other LSI. MST2000 is upper compatible with the predecessor LTS2020 and it offers high cost performance, high throughput and compact system with the help of original family board architecture. Especially it is useful for the devices of defense and aerospace application to fulfill the reliability test which is also the high-mix and low volume testing. The reason why MST2000 is useful for defense and aerospace application testing is because MST2000 test system can be re-formed by the components consisting of family board, socket assembly and DUT board.



Semiconductor Manufacturing Process (※1) SOC: Silicon on Chip

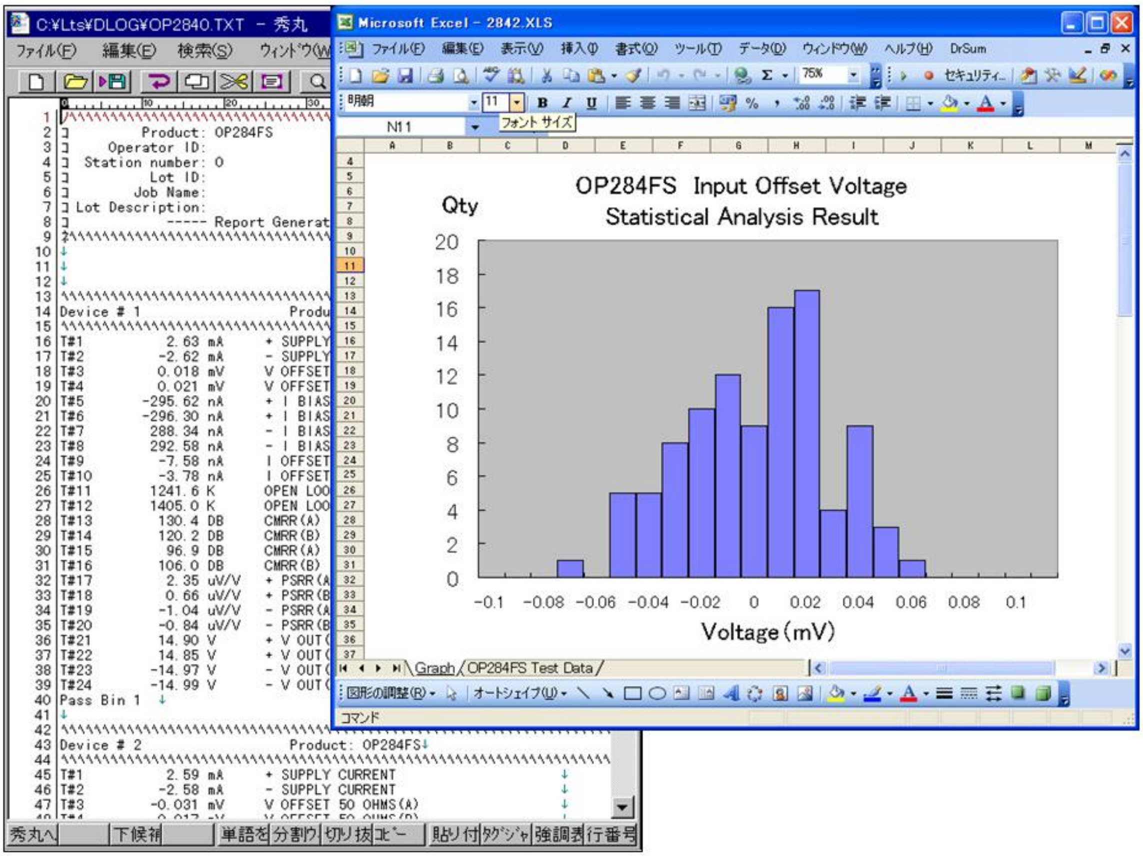
- ■ Low cost, bench-top, all-in-one LSI tester
- ■ DC Parametric Test
- ■ Auto calibration, high precision ±(0.0015%±100uV)
- ■ Family boards architecture for useful functions
- ■ Based on Windows OS, easy operation by pull-down menu
- ■ Powerful test program development tools by C language
- ■ Devices being tested : OPAMP, regulator, Linear LSI, A/D converter, D/A converter, Logic LSI, ASSP, etc.
- ■ High cost performance

● MST2000 LSI Tester Specifications

	Range	Resolution	Accuracy
DC Voltage Measure	±10Vmax	16bit	±(0.001＋100uV)
High precision V Source A	±10V, +10V	16bit	±(0.001＋100uV)
Quad V Source	0～＋20V, 2ch	12bit	±0.25%FS
	－20～0V, 2ch	12bit	±0.25%FS
High precision V Source(SR)	－10～＋10V	16bit	±0.001%FS
Source TH(VTH)	0～＋10V	8bit	±0.25%FS
Digital Drivers	Channels	24	
	Output Transistor Characteristic	VCEmax=30V, 1Limit=200mA(VCE(SAT)=0.7V)	
Digital Inputs	Channels	24	
	Input Threshold	0～＋10V	
Weight	Test Head	10Kg	
	Power Head	40Kg	
Size	Test Head	W498×D499×H270	
	Power Head	W498×D499×H160	

● Edit of Log data set

Log data set being composed of text data, they can be easily transferred to other standard Windows applications such as Excel, Access, etc.



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ｺ          Product: OP284FS
ｺ      Operator ID:
ｺ   Station number: 0
ｺ           Lot ID:
ｺ         Job Name:
ｺ Lot Description:
ｺ             ------ Report Generat
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Device # 1                      Produ
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T#1            2.63 mA     + SUPPLY
T#2           -2.62 mA     - SUPPLY
T#3           0.018 mV     V OFFSET
T#4           0.021 mV     V OFFSET
T#5         -295.62 nA     + I BIAS
T#6         -296.30 nA     + I BIAS
T#7          288.34 nA     - I BIAS
T#8          292.58 nA     - I BIAS
T#9           -7.58 nA     I OFFSET
T#10          -3.78 nA     I OFFSET
T#11         1241.6 K      OPEN LOO
T#12         1405.0 K      OPEN LOO
T#13          130.4 DB     CMRR(A)
T#14          120.2 DB     CMRR(B)
T#15           96.9 DB     CMRR(A)
T#16          106.0 DB     CMRR(B)
T#17           2.35 uV/V   + PSRR(A
T#18           0.66 uV/V   + PSRR(B
T#19          -1.04 uV/V   - PSRR(A
T#20          -0.84 uV/V   - PSRR(B
T#21          14.90 V      + V OUT(
T#22          14.85 V      + V OUT(
T#23         -14.97 V      - V OUT(
T#24         -14.99 V      - V OUT(
Pass Bin 1  ↓
↓
^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^
Device # 2                      Product: OP284FS↓
^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^^
T#1            2.59 mA     + SUPPLY CURRENT                       ↓
T#2           -2.58 mA     - SUPPLY CURRENT                       ↓
T#3          -0.031 mV     V OFFSET 50 OHMS(A)                    ↓
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- **Design of test package consisting of H/W and S/W**

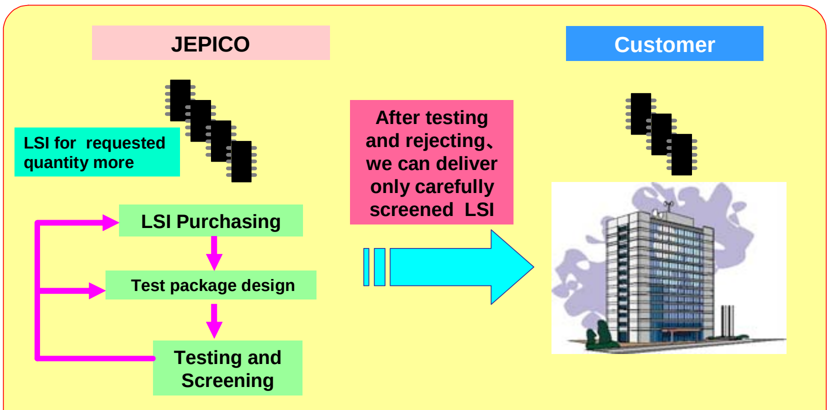
If you have already had MST-2000 system, we can offer the test package design by utilizing our testing know-how and testing library. Responding to the customer's specifications, we can flexibly offer test board design, test programming, highly specific test package (for example temperature testing) and documentation management.

- **LSI purchasing, testing and supplying in a lump like a one-stop shop**

We will act for the customer's LSI purchasing, testing and supplying. It will cut through the red tape.

- ■ LSI purchasing under the optimal conditions
- ■ Drawing of test specifications, design of test package
- ■ Documentation works

LSI purchasing, testing and supplying in a lump like a One-stop shop



In this comprehensive solution, it is not necessary for customer to take a time of screening and to have a shortage of screened devices.

Contact

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